

January 2014

# FQD12N20L

# N-Channel QFET® MOSFET

200 V, 9.0 A, 280 mΩ

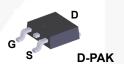
# **Description**

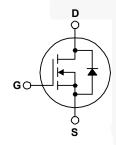
This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state

• Low Gate Charge (Typ. 16 nC) resistance, and to provide superior switching performance • Low Crss (Typ. 17 pF) and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power • 100% Avalanche Tested factor correction (PFC), and electronic lamp ballasts.

### **Features**

- 9.0 A, 200 V,  $R_{DS(on)}$  = 280 m $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_D = 4.5 A$





## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted.

| Symbol                            | Parameter   |          | FQD12N20LTM | Unit |  |
|-----------------------------------|---|----------|-------------|------|--|
| $V_{DSS}$                         | Drain-Source Voltage  |          | 200         | V    |  |
| I <sub>D</sub>                    | Drain Current - Continuous (T <sub>C</sub> = 25°C)                                  |          | 9.0         | Α    |  |
|                                   | - Continuous (T <sub>C</sub> = 100°C)   |          | 5.7         | Α    |  |
| I <sub>DM</sub>                   | Drain Current - Pulsed  | (Note 1) | 36          | Α    |  |
| V <sub>GSS</sub>                  | Gate-Source Voltage   |          | ± 20        | V    |  |
| E <sub>AS</sub>                   | Single Pulsed Avalanche Energy  | (Note 2) | 210         | mJ   |  |
| I <sub>AR</sub>                   | Avalanche Current   | (Note 1) | 9.0         | Α    |  |
| E <sub>AR</sub>                   | Repetitive Avalanche Energy   | (Note 1) | 5.5         | mJ   |  |
| dv/dt                             | Peak Diode Recovery dv/dt (Note 3)  |          | 5.5         | V/ns |  |
| P <sub>D</sub>                    | Power Dissipation (T <sub>A</sub> = 25°C) *   |          | 2.5         | W    |  |
|                                   | Power Dissipation (T <sub>C</sub> = 25°C)   |          | 55          | W    |  |
|                                   | - Derate above 25°C   |          | 0.44        | W/°C |  |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Temperature Range   |          | -55 to +150 | °C   |  |
| T.                                | T <sub>L</sub> Maximum lead temperature for soldering, 1/8" from case for 5 seconds |          | 300         | °C   |  |
| · L                               |   |          | 300         | C    |  |

## **Thermal Characteristics**

| Symbol          | Parameter   | FQD12N20LTM | Unit |
|-----------------|---|-------------|------|
| $R_{\theta JC}$ | Thermal Resistance, Junction to Case, Max.  | 2.27        |      |
| В               | Thermal Resistance, Junction to Ambient (Minimum Pad of 2-oz Copper), Max.            | 110         | °C/W |
| $R_{\theta JA}$ | Thermal Resistance, Junction to Ambient (*1 in <sup>2</sup> Pad of 2-oz Copper), Max. | 50          |      |

# **Package Marking and Ordering Information**

| Part Number | Top Mark  | Package | Packing Method | Reel Size | Tape Width | Quantity   |
|-------------|-----------|---------|----------------|-----------|------------|------------|
| FQD12N20LTM | FQD12N20L | DPAK    | Tape and Reel  | 330 mm    | 16 mm      | 2500 units |

## **Electrical Characteristics**

T<sub>C</sub> = 25°C unless otherwise noted.

| Symbol  | Parameter   | Test Conditions  | Min. | Тур.                 | Max.                | Uni         |
|---|---|--|------|----------------------|---------------------|-------------|
| Off Cha   | aracteristics   |  |      |                      |                     |             |
| BV <sub>DSS</sub>   | Drain-Source Breakdown Voltage  | V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA   | 200  |                      |                     | V           |
| ΔBV <sub>DSS</sub><br>/ ΔT <sub>J</sub>                                 | Breakdown Voltage Temperature<br>Coefficient  | I <sub>D</sub> = 250 μA, Referenced to 25°C  |      | 0.14                 |                     | V/°C        |
| I <sub>DSS</sub>  | Zoro Cata Valtaga Prain Current   | V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V   |      | -                    | 1                   | μΑ          |
|   | Zero Gate Voltage Drain Current   | V <sub>DS</sub> = 160 V, T <sub>C</sub> = 125°C  |      |                      | 10                  | μΑ          |
| I <sub>GSSF</sub>   | Gate-Body Leakage Current, Forward  | V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V  |      |                      | 100                 | nA          |
|   |   |  |      |                      | -100                | nΑ          |
| I <sub>GSSR</sub>   | Gate-Body Leakage Current, Reverse  | V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V   |      |                      | -100                | 117         |
|   |   | V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V   |      |                      | -100                | 11/-        |
| On Cha  | aracteristics Gate Threshold Voltage  | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA  | 1.0  |                      | 2.0                 | V           |
|   | racteristics  | $V_{DS} = V_{GS}, I_D = 250 \mu A$ $V_{GS} = 10 \text{ V}, I_D = 4.5 \text{ A}$ $V_{GS} = 5 \text{ V}, I_D = 4.5 \text{ A}$  |      | <br>0.22<br>0.25     | 1.00                |             |
| On Cha  | Gate Threshold Voltage Static Drain-Source  | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA<br>V <sub>GS</sub> = 10 V, I <sub>D</sub> = 4.5 A  | 1.0  | 0.22                 | 2.0                 | V           |
| On Cha<br>V <sub>GS(th)</sub><br>R <sub>DS(on)</sub><br>g <sub>FS</sub> | Gate Threshold Voltage Static Drain-Source On-Resistance  | $V_{DS} = V_{GS}, I_D = 250 \mu A$ $V_{GS} = 10 \text{ V}, I_D = 4.5 \text{ A}$ $V_{GS} = 5 \text{ V}, I_D = 4.5 \text{ A}$  | 1.0  | 0.22<br>0.25         | 2.0<br>0.28<br>0.32 | V           |
| On Cha  | Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance                     | $V_{DS} = V_{GS}, I_D = 250 \mu A$ $V_{GS} = 10 \text{ V}, I_D = 4.5 \text{ A}$ $V_{GS} = 5 \text{ V}, I_D = 4.5 \text{ A}$  | 1.0  | 0.22<br>0.25         | 2.0<br>0.28<br>0.32 | V           |
| On Cha<br>V <sub>GS(th)</sub><br>R <sub>DS(on)</sub><br>g <sub>FS</sub> | Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance  ic Characteristics | $V_{DS} = V_{GS}$ , $I_D = 250 \mu A$ $V_{GS} = 10 \text{ V}$ , $I_D = 4.5 \text{ A}$ $V_{GS} = 5 \text{ V}$ , $I_D = 4.5 \text{ A}$ $V_{DS} = 30 \text{ V}$ , $I_D = 4.5 \text{ A}$ | 1.0  | 0.22<br>0.25<br>11.6 | 2.0<br>0.28<br>0.32 | V<br>Ω<br>S |

# **Switching Characteristics**

|                     | _                   |  |          |         |     |    |
|---------------------|---------------------|--|----------|---------|-----|----|
| t <sub>d(on)</sub>  | Turn-On Delay Time  | V <sub>DD</sub> = 100 V, I <sub>D</sub> = 11.6 A |          | <br>15  | 40  | ns |
| t <sub>r</sub>      | Turn-On Rise Time   | $R_G = 25 \Omega$                                | ,        | <br>190 | 390 | ns |
| t <sub>d(off)</sub> | Turn-Off Delay Time | G  |          | <br>60  | 130 | ns |
| t <sub>f</sub>      | Turn-Off Fall Time  |  | (Note 4) | <br>120 | 250 | ns |
| $Q_g$               | Total Gate Charge   | V <sub>DS</sub> = 160 V, I <sub>D</sub> = 11.6 A | ,        | <br>16  | 21  | nC |
| Q <sub>gs</sub>     | Gate-Source Charge  | V <sub>GS</sub> = 5 V                            |          | <br>2.8 |     | nC |
| $Q_{gd}$            | Gate-Drain Charge   |  | (Note 4) | <br>7.6 |     | nC |
|                     |                     |  |          |         |     |    |

## **Drain-Source Diode Characteristics and Maximum Ratings**

| IS              | Maximum Continuous Drain-Source Diode Forward Current |   |  |      | 9.0 | Α  |
|-----------------|---|---|--|------|-----|----|
| I <sub>SM</sub> | Maximum Pulsed Drain-Source Diode Forward Current     |   |  |      | 36  | Α  |
| V <sub>SD</sub> | Drain-Source Diode Forward Voltage                    | V <sub>GS</sub> = 0 V, I <sub>S</sub> = 9.0 A   |  |      | 1.5 | V  |
| t <sub>rr</sub> | Reverse Recovery Time                                 | V <sub>GS</sub> = 0 V, I <sub>S</sub> = 11.6 A, |  | 128  |     | ns |
| Q <sub>rr</sub> | Reverse Recovery Charge                               | dI <sub>F</sub> / dt = 100 A/μs                 |  | 0.56 |     | μС |

Notes. In Repetitive rating: pulse width limited by maximum junction temperature. 2. L = 3.9 mH, I $_{AS}$  = 9.0 A, V $_{DD}$  = 50 V, R $_{G}$  = 25  $\Omega$ , starting T $_{J}$  = 25°C. 3. I $_{SD}$   $\leq$  11.6 A, di/dt  $\leq$  300 A/ $\mu$ s, V $_{DD}$   $\leq$  BV $_{DSS}$ , starting T $_{J}$  = 25°C. 4. Essentially independent of operating temperature.

# **Typical Characteristics**

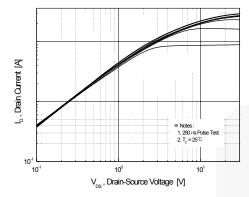


Figure 1. On-Region Characteristics

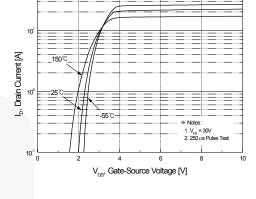


Figure 2. Transfer Characteristics

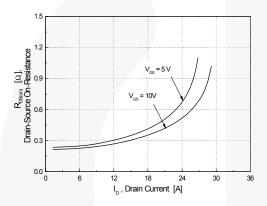


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

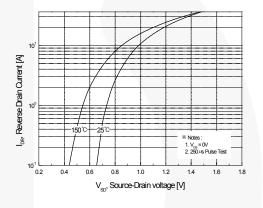


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

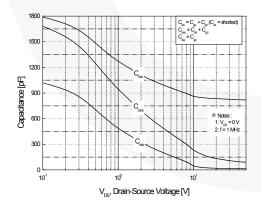


Figure 5. Capacitance Characteristics

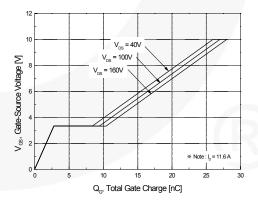


Figure 6. Gate Charge Characteristics

# Typical Characteristics (Continued)

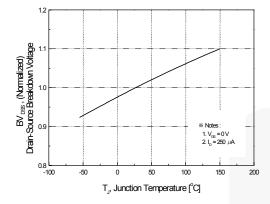


Figure 7. Breakdown Voltage Variation vs. Temperature

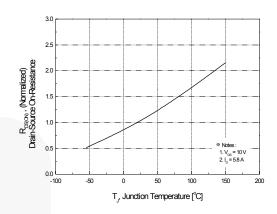


Figure 8. On-Resistance Variation vs. Temperature

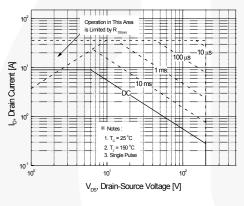


Figure 9. Maximum Safe Operating Area

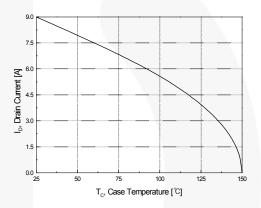


Figure 10. Maximum Drain Current vs. Case Temperature

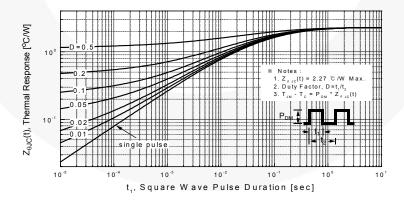


Figure 11. Transient Thermal Response Curve

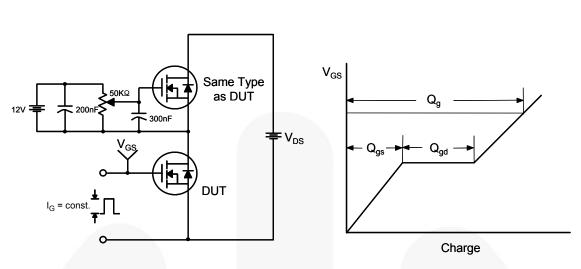


Figure 12. Gate Charge Test Circuit & Waveform

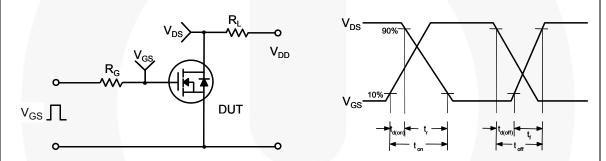


Figure 13. Resistive Switching Test Circuit & Waveforms

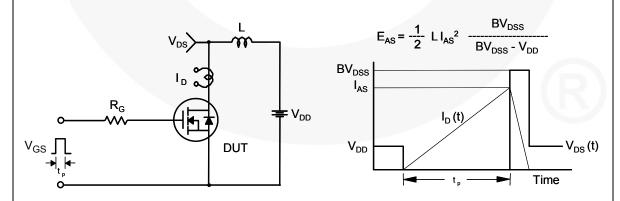
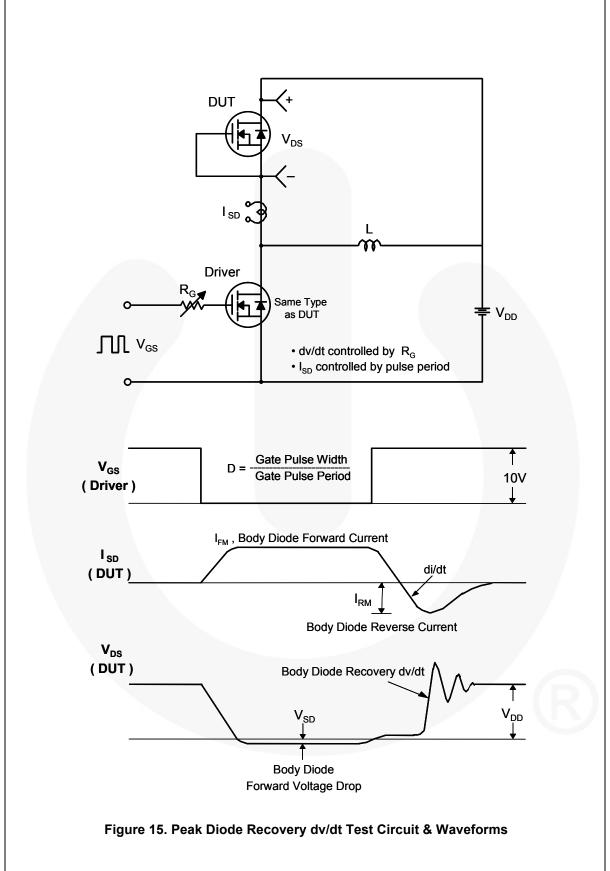


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



## -5.55 MIN→ 1.27 6.22 5.97 6.50 MIN -1.02 MAX Ċ (0.59)0.89 2.29 .25 2.28 ⊕ 0.25 A A C 4.57 LAND PATTERN RECOMMENDATION B 2.39 SFF 2.18 4.32 MIN NOTE D 0.58 0.45 5.21 MIN 10.41 9.40 SFF DFTAIL A ○ 0.10 B 0.51 GAGE PLANE NOTES: UNLESS OTHERWISE SPECIFIED THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA. ALL DIMENSIONS ARE IN MILLIMETERS. 10 (1.54)DIMENSIONING AND TOLERANCING PER ASME Y14.5M-2009. SUPPLIER DEPENDENT MOLD LOCKING HOLES OR CHAMFERED CORNERS OR EDGE PROTRUSION. PRESENCE OF TRIMMED CENTER LEAD .78 .40 0.127 MAX IS OPTIONAL. DIMENSIONS ARE EXCLUSSIVE OF BURSS, MOLD FLASH AND TIE BAR EXTRUSIONS. SEATING PLANE (2.90)LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD DETAIL T0228P991X239-3N. (ROTATED -90°) SCALE: 12X DRAWING NUMBER AND REVISION: MKT-T0252A03REV9. FAIRCHILD SEMICONDUCTOR.

Figure 16. TO252 (D-PAK), Molded, 3-Lead, Option AA&AB

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**Mechanical Dimensions** 





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